

**In the United States Patent and Trademark Office**

In re the application of  
Lee D. Whetsel

TI-25300.2

Serial No.: 10/806,539

Art Unit: 2138

Filed: March 23, 2004

Examiner: S. Radosevich

Title: Probeless Testing of Pad Buffers on Wafer

**Amendment D Under 37 CFR 1.116**

February 15, 2007

Asst. Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

In response to the Examiner's Action of 09/25/2006, please  
amend this application as follows: